

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
219507US2SDIVSERIAL NO.
10/076,284

LIST OF REFERENCES CITED BY APPLICANT

OCT 09 2002

APPLICANT
Hideo ANDO, et al.FILING DATE
February 19, 2002GROUP
2615

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HU</i>	AA	5,712,947	27Jan98	<u>Oguro, et al.</u>	—	—	
<i>HU</i>	AB	6,385,389 B1	07May02	<u>Maruyama, et al.</u>	—	—	
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>HU</i>	AG	EP 1 065 665 A1	03Jan01	European Patent Office (in English)		
<i>HU</i>	AH	JP 5-165935	2Jul93	JAPAN	x	
<i>HU</i>	AI	JP 5-81787	02Apr93	JAPAN	x	
<i>HU</i>	AJ	JP 7-143429	02Jun95	JAPAN	x	
<i>HU</i>	AK	JP 8-106721	23Apr96	JAPAN	x	
<i>HU</i>	AL	JP 9-259539	03Oct97	JAPAN	x	
<i>HU</i>	AM	JP 11-215471	6Aug99	JAPAN (corresponding U.S. Patent no. 6,385,389 B1 <u>Maruyama, et al.</u>)		x
<i>HU</i>	AN	JP 11-238362	31Aug99	JAPAN (corresponding European Patent No. EP 1 065 665, <u>ANDO, et al.</u>)		x
	AO					
	AP					
	AQ					
	AR					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>HU</i>	AS	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310033 (with English translation)				
<i>HU</i>	AT	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310034 (with English translation)				
<i>HU</i>	AU	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310035 (with English translation)				
<i>HU</i>	AV	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310036 (with English translation)				
<i>HU</i>	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310037 (with English translation)				
	AX					<input type="checkbox"/> Additional References sheet(s) attached

Examiner

HUY NGUYEN

Date Considered

11/1/03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219507US2SDIV		SERIAL NO. 10/076,284	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE February 19, 2002		GROUP 2615	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>idw</i>	AA	5,712,947	27Jan98	Oguro, et al.	—	—	
<i>idw</i>	AB	6,385,389 B1	07May02	Maruyama, et al.	—	—	
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<i>idw</i>	AG	EP 1 065 665 A1	03Jan01	European Patent Office (In English)			
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Examiner <i>HUY NGUYEN</i>					Date Considered <i>12/20/04</i>		
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PATENT-219507US219507PTO-1449.doc

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219507US2S DIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
<i>Hu</i>	AA	5,687,160	11/97	Aotake et al.	1	1	
<i>Hu</i>	AB	5,731,852	03/98	Lee	1	1	
<i>Hu</i>	AC	6,185,365	02/01	Murase et al.	1	1	
<i>Hu</i>	AD	6,067,400	05/00	Saeki et al.	1	1	
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<i>Hu</i>	AO 7-143429	06-02-95	JAPAN				X
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 11002 U.S. PTO
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 02/19/02